PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

**CONTINUING DATA VERIFIED: THIS APPLIN CLAIMS BENEFIT OF 60/248,170 11/13/2000  **BEST AVAILABLE COPY  **FOREIGN APPLICATIONS VERIFIED:	APPL NUM 10029788	FILING DATE 10/26/2001	CLASS 451	SUBCLASS 044	GAU 37 <del>23</del>	Eley	
BEST AVAILABLE COPY	APPLICANT	S: Curran [	David; Gu	ıldi Richard; P	ressnall W		
	HIS APPLN C	CLAIMS BENEFIT C	OF 60/248				
* FOREIGN APPLICATIONS VERIFIED:	Æ	BEST AVI	an an	BLE CC	PPY		
	FOREIGN AF	PLICATIONS VER	RIFIED:				
G-PUB DO NOT PUBLISH RESCIND							
oreign priority claimed ☐ yes ☐ no ☐ ATTORNEY DOCKET NO 5 USC 119 conditions met ☐ yes ☐ no TI-29038	JSC 119 conditio fied and Acknow	ons met vledged Examiners's intid	⊒ yes	⊐ no	h	-29038	
TLE: Method and system for reducing thickness of spin-on glass on semiconductor wafers	E: Method a	a <del>nd system</del> for redu	ucing thic	kness of spin-	on glass or	n semiconductor wafers ISDEPT. OF COMM./PAT.& TM-PTO-436L(Re	v 12-94

NOTICE OF ALL	OWANCE MAILED		CLAIMS ALLOWED				
		Assistant Examiner	Total Claims		Print Claim for O.G		
ISS	SUE FEE		DRAWING				
Amount Due	Date Paid		Sheets Drwg.	Figs.Drwg.	Print Fig.		
		Primary Examiner					
TERMINAL		PREPARED FOR ISSUE	Application Examiner				
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